

Date Created : 2008/08/22
Date Issued On : 2008/09/05
PCN# : Q3083404

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:

Name: Choong, CH
E-mail: ch.choong@fairchildsemi.com
Phone:

PCN Originator:

Name: Lim, TengLi
E-mail: TengLi.Lim@notes.fairchildsemi.com
Phone: 604 6437 211 ext 2276

Implementation of change:

Expected 1st Device Shipment Date: 2008/11/20

Earliest Year/Work Week of Changed Product: 0807

Change Type Description: Mold Compound

Description of Change (From): PDIP package assembly at UTAC using non Green mold compound.

Description of Change (To): PDIP package assembly at UTAC using Green mold compound.

Reason for Change : Green initiative by Fairchild Semiconductor. Fairchild Semiconductor is dedicated to being a good corporate citizen. All Fairchild Semiconductor products are 2nd level interconnect lead-free and RoHS compliance. The referenced material changes have been made to provide a ?Full Green? (Halogen Free Flame Retardant) package.

Qual/REL Plan Numbers : Q20070425

Qualification :

Qualification Plan Results are as stated in the Qualification Plan # Q20070425.

Results/Discussion for Qual Plan Number Q20070425

Test: (Gate Leakage Negative)			
Lot	Device	Results	Failure Code
Q20070425AAGATE-	RV4145AN	0/3	
Q20070425BAGATE-	FAN2502S25X	0/3	
Q20070425CAGATE-	MM74C926N	0/3	
Test: (Gate Leakage Positive)			
Lot	Device	Results	Failure Code

Q20070425AAGATE+	RV4145AN	0/3		
Q20070425BAGATE+	FAN2502S25X	0/3		
Q20070425CAGATE+	MM74C926N	0/3		
Test: (High Temperature Storage Life)				
Lot	Device	168-HOURS	1000-HOURS	Failure Code
Q20070425AAHTSL	RV4145AN	0/77		
Q20070425AAHTSL	RV4145AN		0/77	
Q20070425BAHTSL	FAN2502S25X	0/77		
Q20070425BAHTSL	FAN2502S25X		0/77	
Q20070425CAHTSL	MM74C926N	0/77		
Q20070425CAHTSL	MM74C926N		0/77	
Test: (Static Op Life)				
Lot	Device	168-HOURS	1000-HOURS	Failure Code
Q20070425AASOPL1	RV4145AN	4/77		Melted, Evaporated, Or Fused Open
Q20070425AASOPL1	RV4145AN		0/77	
Q20070425BASOPL1	FAN2502S25X	0/77		
Q20070425BASOPL1	FAN2502S25X		0/77	
Q20070425CASOPL1	MM74C926N	0/77		
Q20070425CASOPL1	MM74C926N		0/77	
Test: -65C, 150C (Temperature Cycle)				
Lot	Device	100-CYCLES	500-CYCLES	Failure Code
Q20070425AATMCL1	RV4145AN	0/77		
Q20070425AATMCL1	RV4145AN		0/77	
Q20070425BATMCL1	FAN2502S25X	0/77		
Q20070425BATMCL1	FAN2502S25X		0/77	
Q20070425CATMCL1	MM74C926N	0/77		
Q20070425CATMCL1	MM74C926N		0/77	
Test: 110C (Highly Accelerated Stress Test)				
Lot	Device	264-HOURS		Failure Code
Q20070425CAHAST2	MM74C926N	0/77		
Test: 130C (Highly Accelerated Stress Test)				
Lot	Device	96-HOURS		Failure Code
Q20070425AAHAST1	RV4145AN	0/77		
Q20070425BAHAST1	FAN2502S25X	0/77		
Test: MSL(1), PKG(Small), PeakTemp(260c), Cycles(3) (Precondition)				
Lot	Device	Results		Failure Code
Q20070425AAPCNL1A	RV4145AN	0/308		
Q20070425BAPCNL1A	FAN2502S25X	0/308		
Q20070425CAPCNL1A	MM74C926N	0/308		

Product Id Description : UTAC 8L & 18L PDIP Green EMC.

Affected FSIDs :

FAN1851AN	MM74C922N_F40	MM74C926N
RA9100_32	RV4141AN	RV4145AN
RV4145AN_F091		